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APPLICATION NO.	FILING DA	ATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/771,566	02/03/2004		Nobuaki Teraguchi	245402008300	3733	
25226	7590 0	3/01/2006		EXAM	EXAMINER	
MORRISO	N & FOERSTE	PAREKI	PAREKH, NITIN			
755 PAGE MILL RD PALO ALTO, CA 94304-1018				ART UNIT	PAPER NUMBER	
				2811		
			DATE MAILED: 03/01/2006			

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
Office Action Summany	10/771,566	TERAGUĆHI, NOBUAKI				
Office Action Summary	Examiner	Art Unit				
	Nitin Parekh	2811				
The MAILING DATE of this communication app Period for Reply	The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply					
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).						
Status						
1) Responsive to communication(s) filed on 22 De	Responsive to communication(s) filed on <u>22 December 2005</u> .					
·	· · · · · · · · · · · · · · · · · · ·					
3) Since this application is in condition for allowan	nce this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice under E	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims						
4)⊠ Claim(s) <u>1 and 5-7</u> is/are pending in the application.						
4a) Of the above claim(s) 5 and 6 is/are withdrawn from consideration.						
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>1 and 7</u> is/are rejected.						
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and/or election requirement.						
Application Papers						
9) The specification is objected to by the Examiner	r.					
10)⊠ The drawing(s) filed on <u>03 February 2004</u> is/are	∴ a) accepted or b) objected	d to by the Examiner.				
Applicant may not request that any objection to the o	drawing(s) be held in abeyance. See	e 37 CFR 1.85(a).				
Replacement drawing sheet(s) including the correction	on is required if the drawing(s) is obj	ected to. See 37 CFR 1.121(d).				
11) The oath or declaration is objected to by the Exa	aminer. Note the attached Office	Action or form PTO-152.				
Priority under 35 U.S.C. § 119		·				
12)⊠ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a)⊠ All b)□ Some * c)□ None of:						
1. Certified copies of the priority documents	have been received.	•				
2. Certified copies of the priority documents have been received in Application No						
3. Copies of the certified copies of the priori	3. Copies of the certified copies of the priority documents have been received in this National Stage					
application from the International Bureau (PCT Rule 17.2(a)).						
* See the attached detailed Office action for a list of the certified copies not received.						
Attachment(s)						
1) Notice of References Cited (PTO-892)	4) Interview Summary (Paper No(s)/Mail Da					
 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) 		atent Application (PTO-152)				
Paper No(s)/Mail Date 6) Other:						

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DETAILED ACTION

Request for Continued Examination

1. A request for continued examination (RCE) under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 12-22-05 has been entered. An action on the RCE follows.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 1 and 7 are rejected under 35 U.S.C. 103(a) as being unpatentable over Huang et al. (US Pat. 6693352) in view of Shimada et al. (US Pat. 4289822).
- A. Regarding claims 1 and 7, Huang et al. disclose a contact/electrode structure employing a nitride based semiconductor of III-V group compound (see Fig. 7), the structure comprising:

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- a nitride-based semiconductor layer of III-V group compound (35 in Fig. 7; Col. 4, lines 40-47)
- an electrode/pad comprising the electrode metal (38A in Fig. 7; Col. 5, lines 45-53), and
- a metal oxide (see 37A in Fig. 7; Col. 5 and 6) layer being inserted between the nitride-based semiconductor layer of III-V group compound and the pad/electrode metal, such contact structure inherently forming an interface/oxygen containing/doped nitride semiconductor intermediate layer between the electrode metal and the underlying nitride based semiconductor layer of III-V group compound due to inter-diffusion of oxygen across the interface during a conventional thermal anneal/oxygen/air anneal at predetermined conditions (see Col. 5, line 53- Col. 6, line 8; Col. 11, line 60- Col. 12, line 5)

(Fig. 7 and Fig. 3; Col. 10, lines 42-60; Col. 4, line 24- Col. 6, line 8; Col. 4-11).

Huang et al. fail to teach the metal of the metal oxide including at least one of La, Ce, Pr, Nd, Pm, Sm, Eu, Gd, Tb, Dy, Ho, Er, Tm, Yb and Lu.

Shimada et al. teach photonic/light emitting semiconductor device comprising a variety of low band gap/metal oxides (Col. 3-12) including Cerium/Ce to provide the desired band gap and improved device characteristics (see 39 in Fig. 6; Col. 6, lines 25-45).

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It would have been obvious to a person of ordinary skill in the art at the time invention was made to incorporate the metal of the metal oxide including at least one of La, Ce, Pr, Nd, Pm, Sm, Eu, Gd, Tb, Dy, Ho, Er, Tm, Yb and Lu as taught by Shimada et al. so that the electrical and optical characteristics can be improved in Huang et al's electrode.

B. Regarding claim 1, forming the intermediate layer during a heating process do not distinguish over Huang et al. and Shimada et al., because only the final product/structure is relevant, not forming the intermediate layer using "heating", "laser annealing", "infrared exposure/curing" or "radiation exposure". Note that a "product by process" claim is directed to the product per se, no matter how actually made, In re Hirao, 190 USPQ 15 at 17 (footnote 3). See also In re Brown, 173 USPQ 685; In re Luck, 177 USPQ 523; In re Fessmann, 180 USPQ 324; In re Avery, 186 USPQ 161; In re Wertheim, 191 USPQ 90 (209 USPQ 554 does not deal with this issue); and In re Marrosi et al., 218 USPQ 289, all of which make it clear that it is the patentability of the final product per se which must be determined in a "product by process" claim, and not the patentability of the process, and that an old or obvious product produced by a new method is not patentable as a product, whether claimed in "product by process" claims or not. Note that applicant has the burden of proof in such cases, as the above case law makes clear. See also MPEP 706.03(e).

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Response to Arguments

4. Applicant's arguments with respect to claims 1 and 7 have been considered but

are moot in view of the new ground(s) of rejection.

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Nitin Parekh whose telephone number is 571-272-1663.

The examiner can normally be reached on 09:00AM-05:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Eddie Lee can be reached on 571-272-1732. The fax phone number for the

organization where this application or proceeding is assigned is 703-872-9318.

Information regarding the status of an application may be obtained from the

Patent Application Information Retrieval (PAIR) system. Status information for published

applications may be obtained from either Private PAN or Public PAG. Status information

for unpublished applications is available through Private PAIR only. For more

information about the PAIR system, see http://pair-direct.uspto.gov. Should you have

questions on access to the Private PAG system, contact the Electronic Business Center

(EBC) at 866-217-9197 (toll-free). Any inquiry of a general nature or relating to the

status of this application or proceeding should be directed to the receptionist whose

telephone number is 703-308-0956.

NP

02-25-06

Nutri Pareth

PRIMARY EXAMINER

TECHNOLOGY CENTER 2800